



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

The Lab Worldwide LLC

201 E. Center Street, Suite 1
Tarpon Springs, FL 34689

Fulfills the requirements of

ISO/IEC 17025:2017

and

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 11 August 2028

Certificate Number: AT-3502



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

The Lab Worldwide LLC
201 E. Center Street, Suite 1
Tarpon Springs, FL 34689
Gil Aouizerat gil@pcxco.com 714- 374-3070

TESTING

ISO/IEC 17025 Accreditation Granted: **11 August 2026**

Certificate Number: **AT-3502**

Certificate Expiry Date: **11 August 2028**

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to **The Lab Worldwide LLC** to perform the following AS6171 slash sheet tests:

Non-Destructive

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Visual Inspection	AS6081 AS6171/2 IDEA-STD-1010	Electrical, Electronic and Electromechanical (EEE) Components	Keyence VHX-7000 Series Keyence VK-X3000 Series
Elemental Content by XRF	AS6081 AS6171/3 IDEA-STD-1010		Amptech – XF-A5
Radiographic Examination/ Inspection	AS6081 AS6171/5		Seamark X5600 X-Ray TruView Prime X-Ray
Scanning Electron Microscopy	AS6081, 4.2.6.3 C AS6171/2 IDEA-STD-1010		Phenom ProX Thermo Fisher
Energy Dispersive Spectroscopy	AS6081, 4.2.6.4.5 APCC.1 AS6171/3 IDEA-STD-1010		Phenom ProX Thermo Fisher

Mechanical Testing

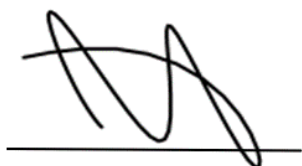
Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Solvent Test for Remarking	AS6081 AS6171/2 IDEA-STD-1010	Electrical, Electronic and Electromechanical (EEE) Components	Mix Solution
Solvent Test for Resurfacing/ Scrape	AS 6081 AS6171/2 IDEA-STD-1010		Acetone 1-Methyl 2- Pyrrolidinone Dynasolve 750 (or equivalent) Hot Plates
Packaging Configuration and Dimension	AS6081 AS6171/2 IDEA-STD-1010		Digital Calipers Keyence VHX-7000 Series Keyence VK-X3000 Series
Solderability	MIL-STD-883 Method 2003.9 ANSI/STD-002		Solder Pot Reflow Oven
Decapsulation and Die Verification	AS6081 AS6171/4		Paragon Oven

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Memory/ Flash/ Programming	Per Customer Specification AS6171/7	Electrical, Electronic and Electromechanical (EEE) Components	Xeltek Programmers
Electrical Characteristics Test (300 Class)	MIL-STD-202G Class 300 AS6171/7		SMUs, Virtual Benches, Electronic Loads, Digital Multimeters, Oscilloscopes, Function Generators, DC Power Supplies, Hipot Testers
Electrical Test (Digital)	MIL-STD-883H Class 3000 AS6171/7		SMUs, Virtual Benches, Electronic Loads, Digital Multimeters, Oscilloscopes, Function Generators, DC Power Supplies, Hipot Testers

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test (Linear)	MIL-STD-883H Class 4000 AS6171/7	Electrical, Electronic and Electromechanical (EEE) Components	SMUs, Virtual Benches, Electronic Loads, Digital Multimeters, Oscilloscopes, Function Generators, DC Power Supplies, Hipot Testers
DDR/SRAM	Per Customer Specification		Eureka Memory Test Systems, Xeltek Programmers
Inductor, Capacitor, and Resistor (LCR) Testing	MIL-STD-202 AS6171/7		LCR Meters
Diode, MOSFET, and Transistor Testing	MIL-STD-750 AS6171/7		Curve Tracers, SMU, Digital Multimeters, Virtual Benches
AC/DC Characteristics Testing	MIL-STD-883 AS6171/7		SMUs, Virtual Benches, Electronic Loads, Digital Multimeters, Oscilloscopes, Function Generators, DC Power Supplies, Hipot Testers
Functional Testing	MIL-STD-883 AS6171/7		SMUs, Virtual Benches, Electronic Loads, Digital Multimeters, Oscilloscopes, Function Generators, DC Power Supplies, Hipot Testers
Advanced Pin Correlation Testing	MIL-STD-883 AS6171/7		XJTAG Boundary Scan Systems, Virtual Benches+ SMUs, Virtual Benches, Electronic Loads, Digital Multimeters, Oscilloscopes, Function Generators, DC Power Supplies, Hipot Testers
RF Testing	MIL-STD-883 AS6171/7		Vector Network Analyzers



Jason Stine, Vice President